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Understanding Embedded - Microprocessors

Embedded microprocessors are specialized computing chips designed to perform specific tasks within an embedded system. Unlike general-purpose microprocessors found in personal computers, embedded microprocessors are tailored for dedicated functions within larger systems, offering optimized performance, efficiency, and reliability. These microprocessors are integral to the operation of countless electronic devices, providing the computational power necessary for controlling processes, handling data, and managing communications.

Applications of Embedded - Microprocessors

Embedded microprocessors are utilized across a broad spectrum of applications, making them indispensable in

Details	
Product Status	Obsolete
Core Processor	PowerPC G4
Number of Cores/Bus Width	1 Core, 32-Bit
Speed	450MHz
Co-Processors/DSP	-
RAM Controllers	-
Graphics Acceleration	No
Display & Interface Controllers	-
Ethernet	-
SATA	-
USB	-
Voltage - I/O	1.8V, 2.5V, 3.3V
Operating Temperature	0°C ~ 105°C (TA)
Security Features	-
Package / Case	360-BCBGA, FCCBGA
Supplier Device Package	360-CBGA (25x25)
Purchase URL	https://www.e-xfl.com/product-detail/nxp-semiconductors/mpc7410hx450le

3 General Parameters

The following list provides a summary of the general parameters of the MPC7410:

Technology	0.18 µm CMOS, six-layer metal
Die size	6.32 mm × 8.26 mm (52 mm^2)
Transistor count	10.5 million
Logic design	Fully static
Packages	Surface mount 360 ceramic ball grid array (CBGA) Surface mount 360 high coefficient of thermal expansion ceramic ball grid array (HCTE_CBGA) Surface mount 360 high coefficient of thermal expansion ceramic ball grid array with lead free C5 spheres (HCTE_CBGA Lead Free C5 Spheres) Surface mount 360 high coefficient of thermal expansion ceramic land grid array (HCTE_LGA)
Core power supply	1.8 V ± 100 mV DC (nominal; see Table 3 for recommended operating conditions)
I/O power supply	1.8 V ± 100 mV DC or 2.5 V ± 100 mV 3.3 V ± 165 mV (system bus only) (input thresholds are configuration pin selectable)

4 Electrical and Thermal Characteristics

This section provides the AC and DC electrical specifications and thermal characteristics for the MPC7410.

4.1 DC Electrical Characteristics

The tables in this section describe the MPC7410 DC electrical characteristics. Table 1 provides the absolute maximum ratings.

Table 1. Absolute Maximum Ratings [1]

Characteristic		Symbol	Maximum Value	Unit	Notes
Core supply voltage		V_{DD}	–0.3 to 2.1	V	4
PLL supply voltage		AV_{DD}	–0.3 to 2.1	V	4
L2 DLL supply voltage		$L2AV_{DD}$	–0.3 to 2.1	V	4
Processor bus supply voltage		OV_{DD}	–0.3 to 3.6	V	3, 6
L2 bus supply voltage		$L2OV_{DD}$	–0.3 to 2.8	V	3
Input voltage	Processor bus	V_{in}	–0.3 to OV_{DD} + 0.2 V	V	2, 5
	L2 bus	V_{in}	–0.3 to $L2OV_{DD}$ + 0.2 V	V	2, 5
	JTAG signals	V_{in}	–0.3 to OV_{DD} + 0.2 V	V	—
Storage temperature range		T_{stg}	–55 to 150	°C	—

Table 2. Input Threshold Voltage Setting

BVSEL Signal [3]	Processor Bus Input Threshold is Relative to:	L2VSEL Signal [3]	L2 Bus Input Threshold is Relative to:	Notes
0	1.8 V	0	1.8 V	1
$\overline{\text{HRESET}}$	2.5 V	$\overline{\text{HRESET}}$	2.5 V	1, 2
1	3.3 V	1	2.5 V	1, 4, 5
¬$\overline{\text{HRESET}}$	3.3 V	¬$\overline{\text{HRESET}}$	Not Supported	6

Notes:

1. **Caution:** The input threshold selection must agree with the OV_{DD}/$L2OV_{DD}$ voltages supplied.
2. To select the 2.5-V threshold option, BVSEL and/or L2VSEL should be tied to $\overline{\text{HRESET}}$ so that the two signals change state together. This is the preferred method for selecting this mode of operation.
3. To overcome the internal pull-up resistance, a pull-down resistance less than 250 Ω should be used.
4. Default voltage setting if left unconnected (internal pulled-up). MPC7410RX*nnn*LE (Rev 1.4) and later only. Previous revisions do not support 3.3 V OV_{DD}; the default voltage setting if left unconnected is 2.5 V.
5. M*xx*7410*xxnnn*LE (Rev. 1.4) and later only. Previous revisions do not support 3.3 V OV_{DD}; having BVSEL = 1 selects the 2.5-V threshold.
6. M*xx*7410*xxnnn*LE (Rev. 1.4) and later only. Previous revisions do not support BVSEL = ¬$\overline{\text{HRESET}}$. (¬$\overline{\text{HRESET}}$ is the inverse of $\overline{\text{HRESET}}$.)

Table 3 provides the recommended operating conditions for the MPC7410.

Table 4. Package Thermal Characteristics (continued)

Characteristic	Symbol	Value		Unit	Notes
		MPC7410 CBGA	MPC7410 HCTE		
Junction-to-case thermal resistance	$R_{\theta JC}$	< 0.1	< 0.1	°C/W	4

Notes:

1. Junction temperature is a function of die size, on-chip power dissipation, package thermal resistance, mounting site (board) temperature, ambient temperature, air flow, power dissipation of other components on the board, and board thermal resistance.
2. Per JEDEC JESD51-6 with the board horizontal.
3. Thermal resistance between the die and the printed circuit board per JEDEC JESD51-8. Board temperature is measured on the top surface of the board near the package.
4. Thermal resistance between the active portion of the die and the calculated case temperature at the top of the die. The actual value of R JC is less than 0.1 °C/W.

Note: Refer to Section 8.8, "Thermal Management Information," for details on thermal management.

Table 5 provides the DC electrical characteristics for the MPC7410.

Table 5. DC Electrical Specifications

At recommended operating conditions (see Table 3)

Characteristic	Nominal Bus Voltage[1]	Symbol	Min	Max	Unit	Notes
Input high voltage (all inputs except SYSCLK)	1.8	V_{IH}	$0.65 \times (L2)OV_{DD}$	$(L2)OV_{DD} + 0.2$	V	2, 3, 8
	2.5	V_{IH}	1.7	$(L2)OV_{DD} + 0.2$		
	3.3	V_{IH}	2.0	$OV_{DD} + 0.3$		
Input low voltage (all inputs except SYSCLK)	1.8	V_{IL}	–0.3	$0.35 \times (L2)OV_{DD}$	V	8
	2.5	V_{IL}	–0.3	$0.2 \times (L2)OV_{DD}$		
	3.3	V_{IL}	–0.3	0.8		
SYSCLK input high voltage	1.8	CV_{IH}	1.5	$OV_{DD} + 0.2$	V	2, 8
	2.5	CV_{IH}	2.0	$OV_{DD} + 0.2$		
	3.3	CV_{IH}	2.4	$OV_{DD} + 0.3$		
SYSCLK input low voltage	1.8	CV_{IL}	–0.3	0.2	V	8
	2.5	CV_{IL}	–0.3	0.4		
	3.3	CV_{IL}	–0.3	0.4		
Input leakage current, $V_{in} = L2OV_{DD}/OV_{DD}$	1.8	I_{in}	—	20	µA	2, 3, 6, 7
	2.5	I_{in}	—	35		
	3.3	I_{in}	—	70		

Table 9. L2CLK Output AC Timing Specifications (continued)

At recommended operating conditions (see Table 3)

Parameter	Symbol	400 MHz		450 MHz		500 MHz		Unit	Notes
		Min	Max	Min	Max	Min	Max		
L2CLK_OUT output jitter	—	—	±150	—	±150	—	±150	ps	6

Notes:

1. L2CLK outputs are L2CLK_OUTA, L2CLK_OUTB, and L2SYNC_OUT pins. The L2CLK frequency to core frequency settings must be chosen such that the resulting L2CLK frequency and core frequency do not exceed their respective maximum or minimum operating frequencies. The maximum L2CLK frequency will be system dependent. L2CLK_OUTA and L2CLK_OUTB must have equal loading.
2. The nominal duty cycle of the L2CLK is 50% measured at midpoint voltage.
3. The DLL-relock time is specified in terms of L2CLKs. The number in the table must be multiplied by the period of L2CLK to compute the actual time duration in ns. Relock timing is guaranteed by design and characterization.
4. The L2CR[L2SL] bit should be set for L2CLK frequencies less than 150 MHz. This adds more delay to each tap of the DLL.
5. Allowable skew between L2SYNC_OUT and L2SYNC_IN.
6. Guaranteed by design and not tested. This output jitter number represents the maximum delay of one tap forward or one tap back from the current DLL tap as the phase comparator seeks to minimize the phase difference between L2SYNC_IN and the internal L2CLK. This number must be comprehended in the L2 timing analysis. The input jitter on SYSCLK affects L2CLK_OUT and the L2 address/data/control signals equally and, therefore, is already comprehended in the AC timing and does not have to be considered in the L2 timing analysis.

The L2CLK_OUT timing diagram is shown in Figure 7.

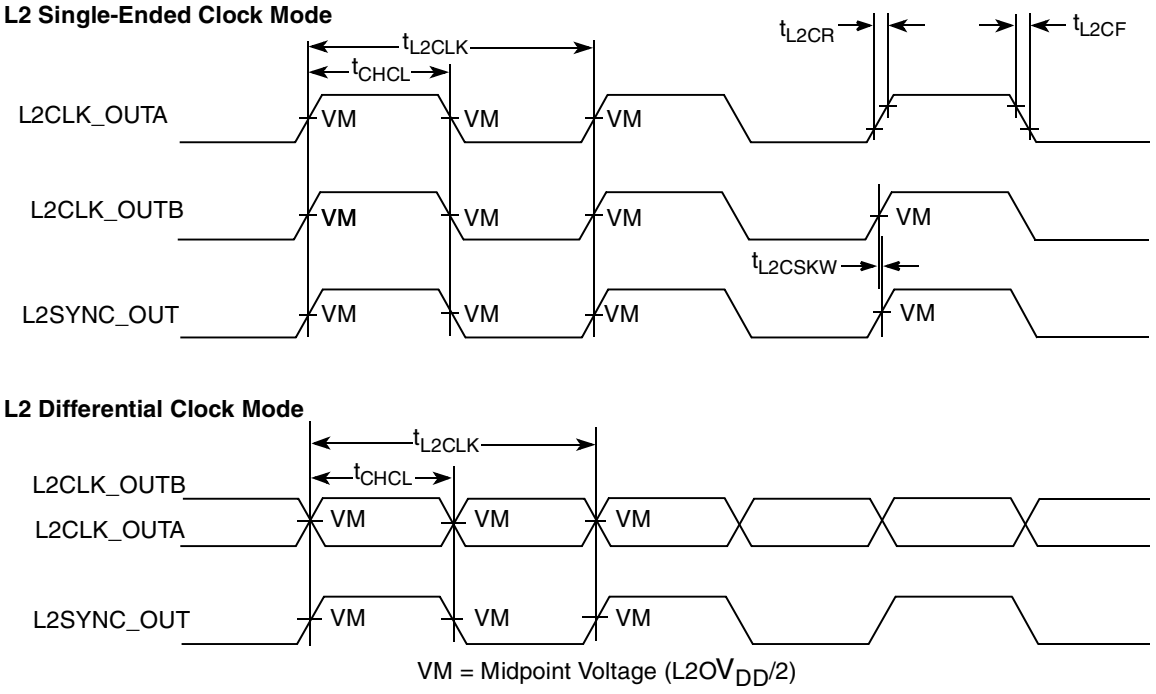


Figure 7. L2CLK_OUT Output Timing Diagram

Figure 8 shows the L2 bus input timing diagrams for the MPC7410.

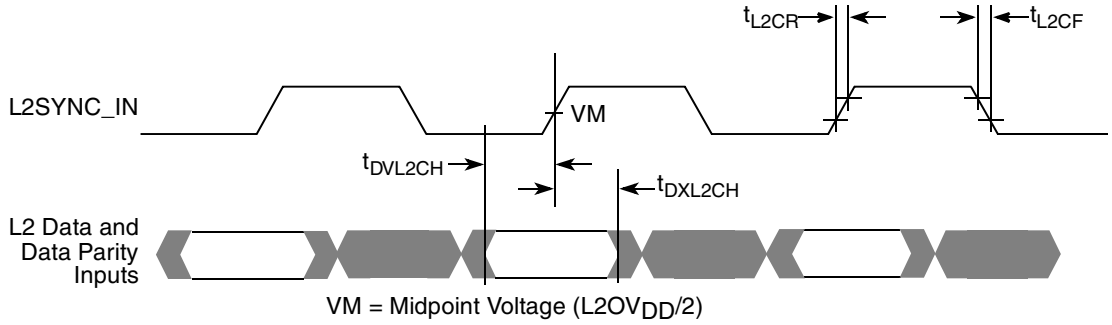


Figure 8. L2 Bus Input Timing Diagrams

Figure 9 shows the L2 bus output timing diagrams for the MPC7410.

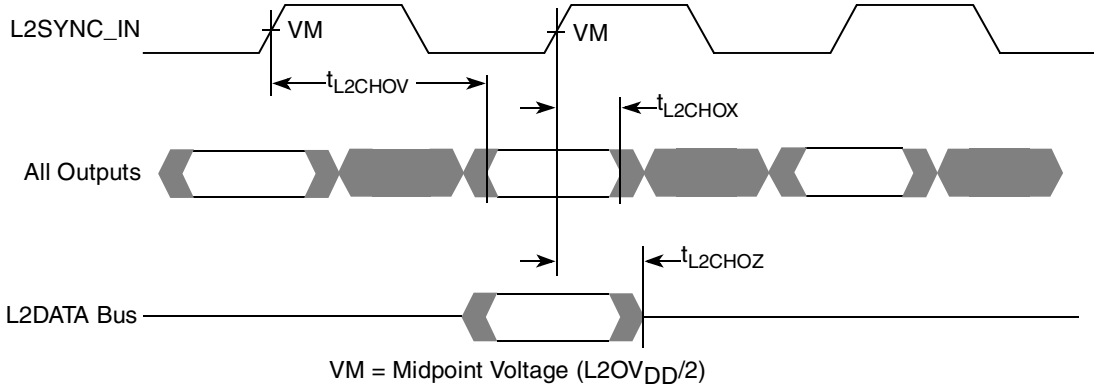


Figure 9. L2 Bus Output Timing Diagrams

Figure 10 provides the AC test load for L2 interface of the MPC7410.

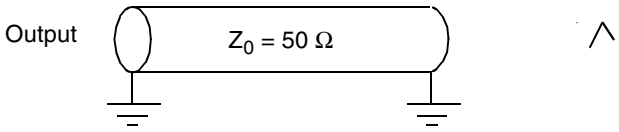


Figure 10. AC Test Load for the L2 Interface

4.2.5 IEEE 1149.1 AC Timing Specifications

Table 11 provides the IEEE 1149.1 (JTAG) AC timing specifications as defined in Figure 12 through Figure 15.

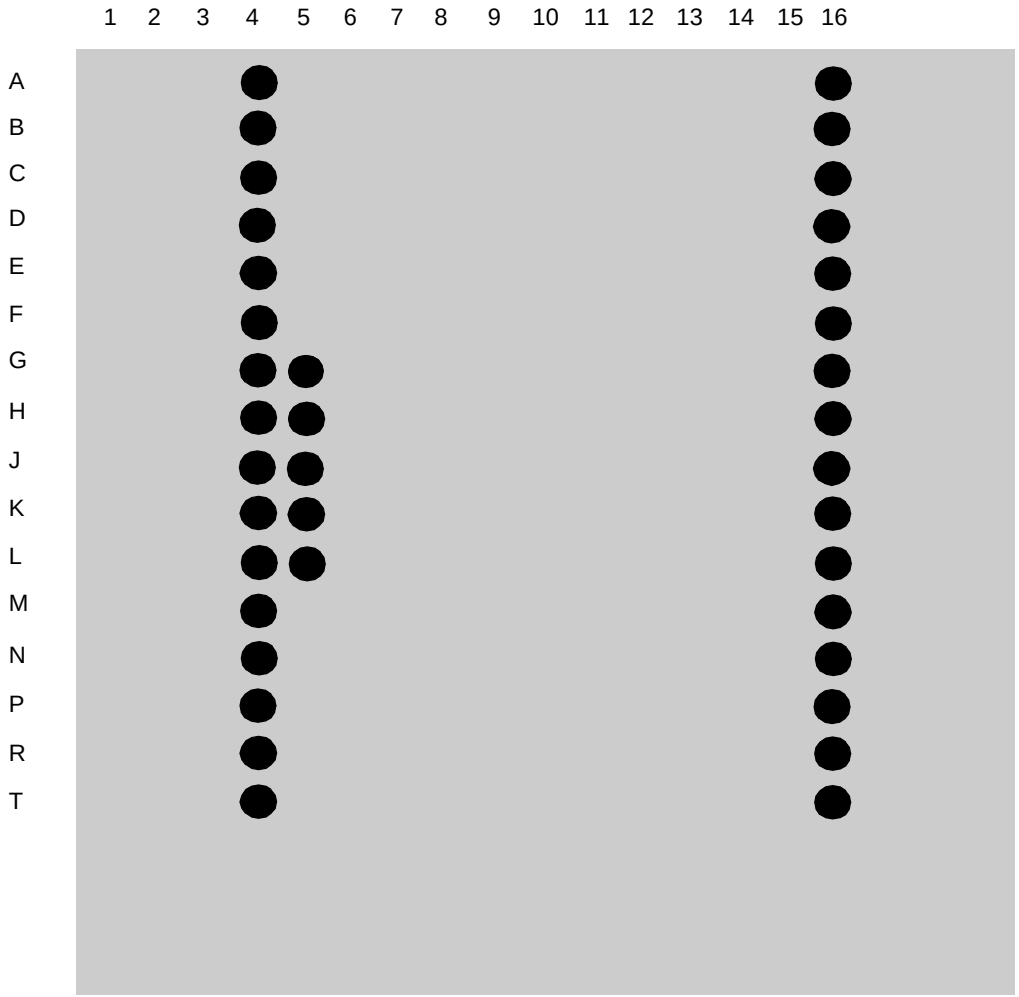
Table 11. JTAG AC Timing Specifications (Independent of SYSCLK) [1]

At recommended operating conditions (see Table 3)

Parameter	Symbol	Min	Max	Unit	Notes
TCK frequency of operation	f_{TCLK}	0	33.3	MHz	—
TCK cycle time	t_{TCLK}	30	—	ns	—
TCK clock pulse width measured at $OV_{DD}/2$	t_{JHJL}	15	—	ns	—
TCK rise and fall times	t_{JR} and t_{JF}	0	2	ns	—

5 Pin Assignments

Figure 16, part A shows the pinout for the MPC7410, 360 CBGA, 360 HCTE, and 360 HCTE Lead Free C5 Spheres packages as viewed from the top surface. Figure 16, part B shows the side profile of the CBGA and HCTE_CBGA packages to indicate the direction of the top surface view. Figure 16, part C shows the side profile of the HCTE_LGA package to indicate the direction of the top surface view.



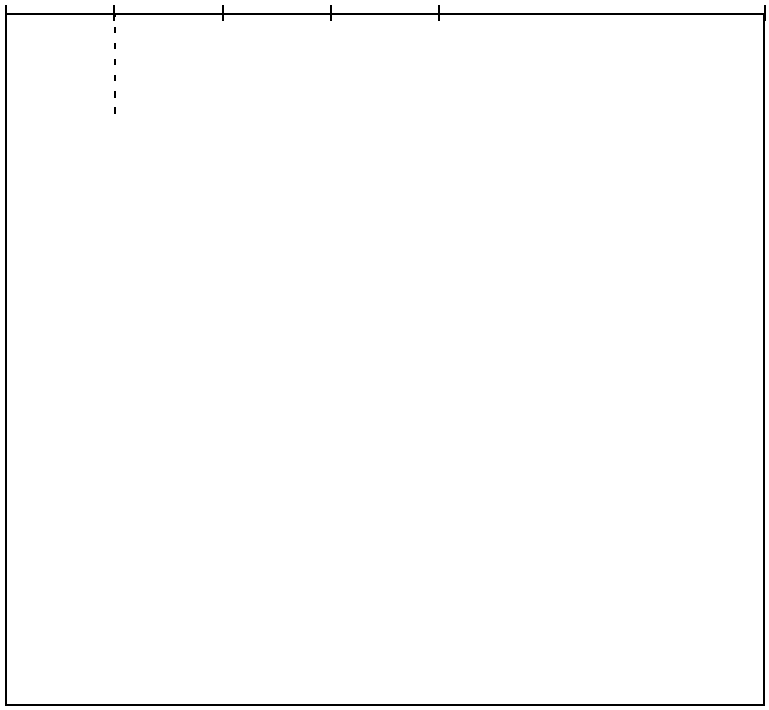


Figure 30. Thermalloy #2328B Heat Sink-to-Ambient Thermal Resistance Versus Airflow Velocity

Though the die junction-to-ambient and the heat sink-to-ambient thermal resistances are a common figure-of-merit used for comparing the thermal performance of various microelectronic packaging technologies, one should exercise caution when only using this metric in determining thermal management because no single parameter can adequately describe three-dimensional heat flow. The final die-junction operating temperature, is not only a function of the component-level thermal resistance, but the system-level design and its operating conditions. In addition to the component's power consumption, a number of factors affect the final operating die-junction temperature—airflow, board population (local heat flux of adjacent components), heat sink efficiency, heat sink attach, heat sink placement, next-level interconnect technology, system air temperature rise, altitude, and so on.

Due to the complexity and the many variations of system-level boundary conditions for today's microelectronic equipment, the combined effects of the heat transfer mechanisms (radiation, convection, and conduction) may vary widely. For these reasons, we recommend using conjugate heat transfer models for the board, as well as, system-level designs.

5	4/13/2005	Section numbering revised. In all previous versions, section numbering began with ‘1.’ These extra ‘1’s’ were deleted. For example, previously numbered section 1.8.2 changed to 8.2. Section 7.1—added CTE value for HCTE package. Corrected minimum module height from 2.65 mm to 2.72 mm per Figure 17. Section 3—added HCTE_LGA (VS package descriptor) package description which is the HCTE_CBGA (HX package descriptor) with the spheres removed. Table 4—generalized ‘HCTE CBGA’ column to ‘HCTE’ to include both HCTE_CBGA and HCTE_LGA package thermal characteristics. Section 5—added HCTE_LGA package. The HCTE_LGA has the same pin assignments as the CBGA and HCTE_CBGA packages. Added side view Part C for HCTE_LGA.

Table 16. Document Revision History (continued)

Revision	Date	Substantive Change(s)
0.3	—	Added 3.3 V support on the processor bus (BVSEL).
		Table 7—update typical and maximum power numbers for full-on mode in. Removed note 4. Reworded notes 2 and 3.
		Table 9, Note 2—removed reference to application note.
		Figure 17—corrected side view datum A to be datum C.
		Section 1.8.7—added $\overline{CI}$ and $\overline{WT}$ to transfer attribute signals requiring pull-ups.
		Section 1.8.7—added 1-kΩ pull-up recommendation to $\overline{GBL}$ when $\overline{GBL}$ is not connected.
		Table 2— added pull-down resistance necessary for internally pulled-up voltage select pins. Added 3.3-V support for BVSEL.
		Table 13—added note 14 for BVSEL, L2VSEL, and $\overline{TRST}$ pins to address pull-down resistance necessary for these internally pulled-up pins to recognize a low signal.
		Table 6—lowered 2.5 V CV_{IH} from 2.2 to 2.0 V to be compatible with V_{OH} of the MPC107. Added support for 3.3-V processor bus.
		Table 15—modified note 1, use L2CR[L2SL] for L2CLK frequency less than 150 MHz.
		Table 8—revised note 2 discussing for 3.3-V bus voltage support.
		Table 14—added note 5, do not use PL off during power-up sequence.
		Table 1—update output hold times (t_{L2CHOX}).
0.2	—	Corrected Section 1.3—technology from 0.13 µm to 0.18 µm.
		Updated Table 7—adds power consumption numbers; adds note on estimated decrease w/o AltiVec.
		Updated Table 8—adds minimum values for processor frequency and VCO frequency.
		Updated Table 9—input setup, output valid times, output hold times, SYSCLK to output high impedance.
		Updated Table 11—L2SYNC_IN to high impedance.
		Updated Figure 17—mechanical dimensions, adds capacitor pad dimensions.
0.1	—	Minor updates.
0	—	Initial release.